



US 20240223202A1

(19) **United States**

(12) **Patent Application Publication**  
**LI et al.**

(10) **Pub. No.: US 2024/0223202 A1**

(43) **Pub. Date: Jul. 4, 2024**

(54) **METHOD FOR CALIBRATING  
ANALOG-TO-DIGITAL CONVERTER**

**Related U.S. Application Data**

(63) Continuation of application No. PCT/CN2023/096785, filed on May 29, 2023.

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(30) **Foreign Application Priority Data**

Dec. 31, 2022 (CN) ..... 202211737070.6

**Publication Classification**

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(51) **Int. Cl.**  
**H03M 1/10** (2006.01)  
(52) **U.S. Cl.**  
CPC ..... **H03M 1/1057** (2013.01)

(57) **ABSTRACT**

A method for calibrating an analog-to-digital converter includes the following steps: conducting an initial performance test and judgement on the analog-to-digital converter; if the initial performance test succeeds, performing a pre-trimming and judgement on the analog-to-digital converter; if the pre-trimming succeeds, performing an error extraction on the analog-to-digital converter, obtaining errors of conversion stages of the analog-to-digital converter; performing an error soft trimming and test on the analog-to-digital converter according to the errors of the conversion stages; and if the error soft trimming and test of the analog-to-digital converter succeed, performing an error hard trimming and test on the analog-to-digital converter according to the errors of the conversion stages.

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(21) Appl. No.: **18/399,607**

(22) Filed: **Dec. 28, 2023**

